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Anmeldung Nr./Application No./Demande n°/Patent. Nr./Patent No./Brevet n°.

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Anmelder/Applicant/Demandeur/Patentinhaber/Propriétaire/Titulaire

ASML Netherlands B.V.

COMMUNICATION

The European Patent Office herewith transmits as an enclosure the European search report for the above-mentioned European patent application.

If applicable, copies of the documents cited in the European search report are attached.

☒ Additional set(s) of copies of the documents cited in the European search report is (are) enclosed as well.

The following specifications given by the applicant have been approved by the Search Division:

☒ abstract

☒ title

☐ The abstract was modified by the Search Division and the definitive text is attached to this communication.

The following figure will be published together with the abstract:

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REFUND OF THE SEARCH FEE

If applicable under Article 10 Rules relating to fees, a separate communication from the Receiving Section on the refund of the search fee will be sent later.





European Patent
Office

EUROPEAN SEARCH REPORT

Application Number
EP 02 25 5002

DOCUMENTS CONSIDERED TO BE RELEVANT			
Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (Int.Cl.7)
A	US 6 142 641 A (COHEN SIMON J ET AL) 7 November 2000 (2000-11-07) * column 8, line 31 - column 12, line 47 *	1-8	G03F7/20
A	RAY-CHAUDHURI A K ET AL: "ALIGNMENT OF A MULTILAYER-COATED IMAGING SYSTEM USING EXTREME ULTRAVIOLET FOUCAULT AND RONCHI INTERFEROMETRIC TESTING" JOURNAL OF VACUUM SCIENCE AND TECHNOLOGY: PART B, AMERICAN INSTITUTE OF PHYSICS. NEW YORK, US, vol. 13, no. 6, 1 November 1995 (1995-11-01), pages 3089-3093, XP000558379 ISSN: 0734-211X * the whole document *	1-8	
A	VAIDYA S ET AL: "Extreme ultraviolet lithography for 0.1 μ m devices" VLSI TECHNOLOGY, SYSTEMS, AND APPLICATIONS, 1999. INTERNATIONAL SYMPOSIUM ON TAIPEI, TAIWAN 8-10 JUNE 1999, PISCATAWAY, NJ, USA, IEEE, US, 8 June 1999 (1999-06-08), pages 127-130, XP010347511 ISBN: 0-7803-5620-9 * paragraph '000B! - paragraph '000C! *	1-8	TECHNICAL FIELDS SEARCHED (Int.Cl.7) G03F
A	US 4 613 230 A (IWAI HIROSHI) 23 September 1986 (1986-09-23) * column 4, line 67 - column 5, line 48; figure 6 *	1-8	
A	US 4 856 905 A (NISHI KENJI) 15 August 1989 (1989-08-15) * the whole document *	1-8	
-/--			
The present search report has been drawn up for all claims			
Place of search MUNICH		Date of completion of the search 8 April 2003	Examiner van Toledo, W
CATEGORY OF CITED DOCUMENTS			
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Application Number
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DOCUMENTS CONSIDERED TO BE RELEVANT			
Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (Int.Cl.7)
A	US 6 151 120 A (INA HIDEKI ET AL) 21 November 2000 (2000-11-21) * column 19, line 36 - line 49 *	1-8	
A	JP 05 160001 A (NIKON CORP) 25 June 1993 (1993-06-25) * abstract *	1-8	
			TECHNICAL FIELDS SEARCHED (Int.Cl.7)
The present search report has been drawn up for all claims			
Place of search MUNICH		Date of completion of the search 8 April 2003	Examiner van Toledo, W
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ON EUROPEAN PATENT APPLICATION NO.**

EP 02 25 5002

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08-04-2003

Patent document cited in search report		Publication date	Patent family member(s)		Publication date
US 6142641	A	07-11-2000	NONE		
US 4613230	A	23-09-1986	JP	1406576 C	27-10-1987
			JP	57183033 A	11-11-1982
			JP	62011780 B	14-03-1987
			JP	58051513 A	26-03-1983
US 4856905	A	15-08-1989	JP	2797250 B2	17-09-1998
			JP	63281427 A	17-11-1988
US 6151120	A	21-11-2000	JP	11162835 A	18-06-1999
JP 05160001	A	25-06-1993	JP	3221057 B2	22-10-2001
			DE	69228338 D1	18-03-1999
			DE	69228338 T2	26-08-1999
			EP	0520625 A1	30-12-1992
			US	5204535 A	20-04-1993